

Notice of References Cited	Application/Control No. 09/940,544	Applicant(s)/Patent Under Reexamination LEE, JOUN HO	
	Examiner Steven H. Rao	Art Unit 2814	Page 1 of 1

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	B	US-6,072,559	06-2000	Kanemori et al.	349/192
	C	US-6,023,310	02-2000	Kawamoto et al.	349/54
	D	US-6,313,889	11-2001	Song et al.	349/54
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.